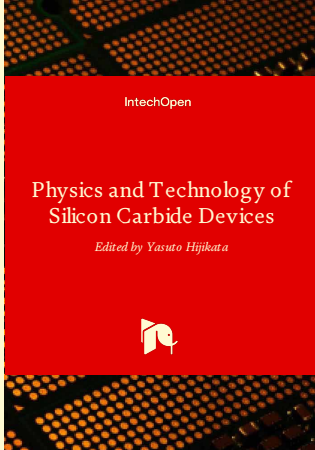


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Authored by: Sadafumi Yoshida, Yasuto Hijikata and Hiroyuki Yaguchi



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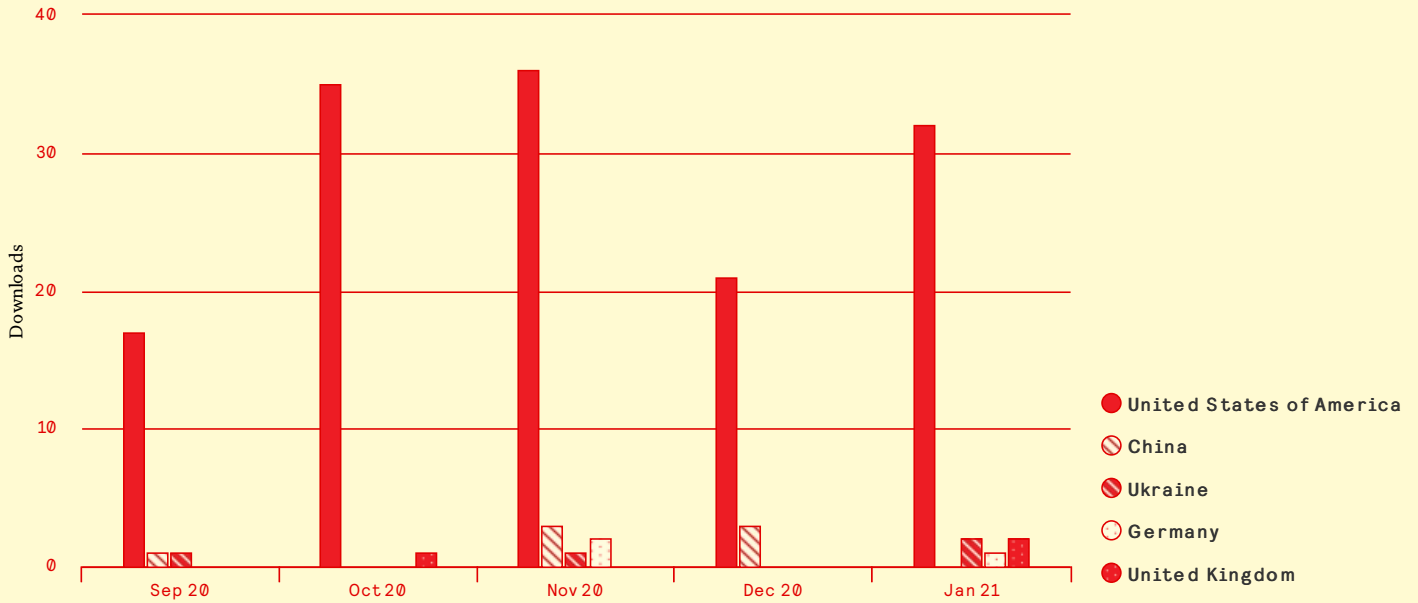


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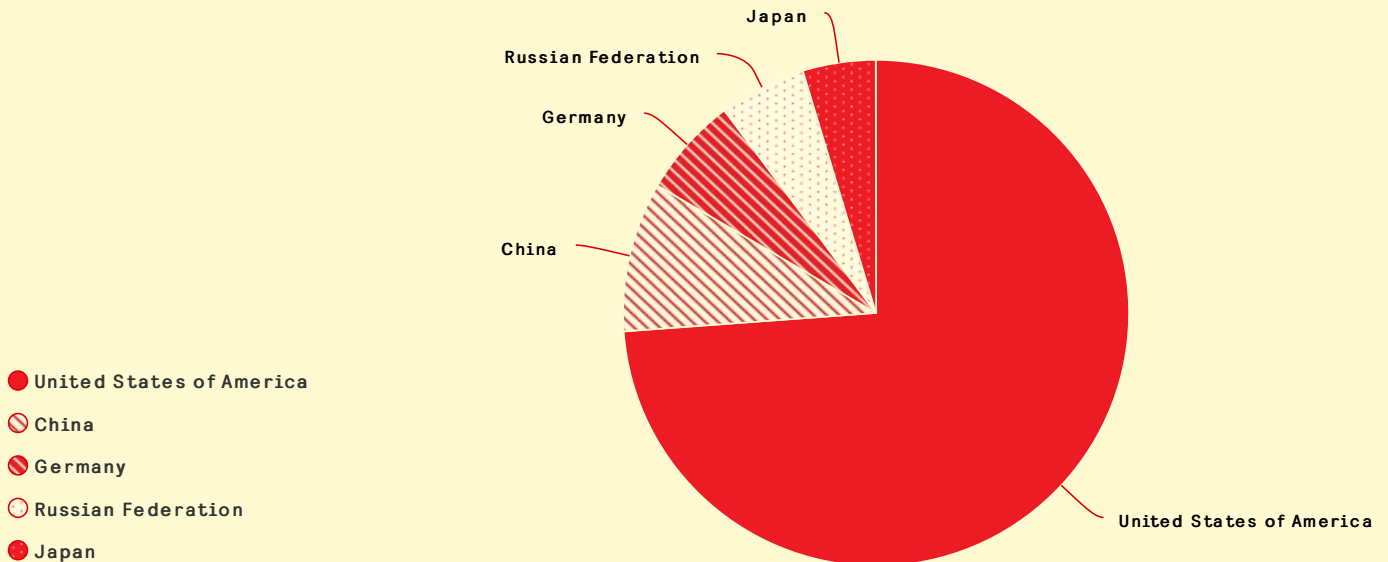
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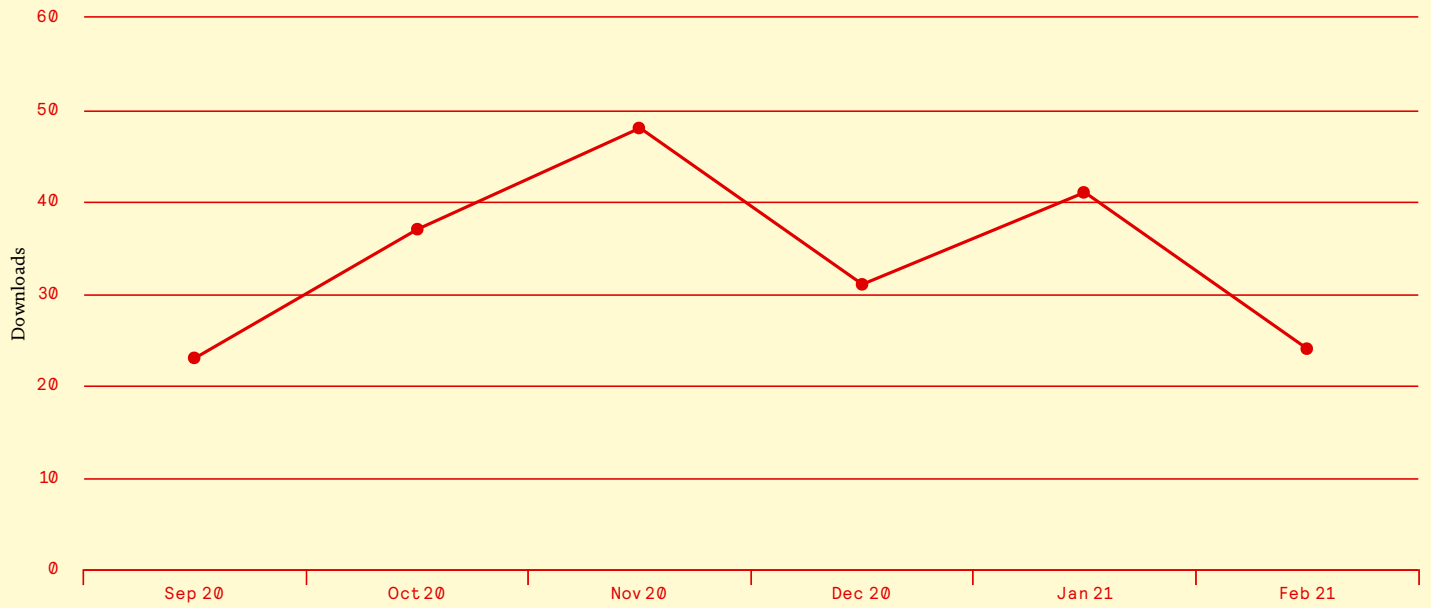
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